

Editorial

**Acknowledgement to Reviewers of *Advances in Environmental and Engineering Research* in 2021***Advances in Environmental and Engineering Research* Editorial OfficeLIDSEN Publishing Inc., 2000 Auburn Drive, One Chagrin Highlands, Suite 200, Beachwood, OH, USA;  
E-Mail: [aeer@lidsen.com](mailto:aeer@lidsen.com)*Adv Environ Eng Res*

2022, volume 3, issue 1

doi:10.21926/aeer.2201001

**Received:** January 06, 2022**Accepted:** January 06, 2022**Published:** January 06, 2022**Abstract**

The editors of *Advances in Environmental and Engineering Research* would like to express their sincere gratitude to the following reviewers for assessing manuscripts in 2021. We greatly appreciate the contribution of expert reviewers, which is crucial to the journal's editorial process. We aim to recognize reviewer contributions through several mechanisms, of which the annual publication of reviewer names is one. Reviewers receive a voucher entitling them to a discount on their next LIDSEN publication and can download a certificate of recognition directly from our submission system. Additionally, reviewers can sign up to the service Publons (<https://publons.com>) to receive recognition. Of course, in these initiatives we are careful not to compromise reviewer confidentiality. Many reviewers see their work as a voluntary and often unseen part of their role as researchers. We are grateful to the time reviewers donate to our journals and the contribution they make.

If you are interested in becoming a reviewer for *Advances in Environmental and Engineering Research*, see the link at the bottom of the webpage <http://www.lidsen.com/joinus>.

The following reviewed for *Advances in Environmental and Engineering Research* in 2021:

Adams, JamesB.	Hu, Zhengyi	Pytharoulis, Ioannis
Albers, Sascha	Hua, Guanghui	Rashid, MuhammadImran
Albini, Angelo	Hussein, Hussam	Ribeiro, FlaviaNoronhaDutra



© 2022 by the author. This is an open access article distributed under the conditions of the [Creative Commons by Attribution License](https://creativecommons.org/licenses/by/4.0/), which permits unrestricted use, distribution, and reproduction in any medium or format, provided the original work is correctly cited.

Amponsah, William	Huthnance, JohnM.	Rigo, Tomeu
Andersen, OleBaltazar	Iacus, StefanoMaria	Saha, Asish
Anderson, RichardH.	Iz, H.Bâki	Sarrà, Montserrat
Aw, TiongGim	Jager, Henriette	Schüpbach, Beatrice
Babaei, Hossein	Kabiri, Keivan	Selisteanu, Dan
Bartolomeo, Nicola	Karagianni, Aikaterini	Shahzad, MuhammadImran
Be'eri-Shlevin, Yaron	Kaskaoutis, Dimitris	Show, PauLoke
Bełdowska, Magdalena	Khwarahm, NabazR.	Smaranda, Camelia
Bełdowski, Jacek	Kowalczyk, Cezary	Smith, SiwapornMeejoo
Bernardi, Bruno	Kurniawan, TonniAgustiono	Song, Zhanlong
Besancenot, JeanPierre	Laca, Amanda	Srebotnjak, Tanja
Bhaganagar, Kiran	Lepine, Christine	Steinemann, Anne
Billock, VincentA.	Li, Ping	Strezov, Vladimir
Chan, YiHerng	Li, Xinghua	Sun, Weiwei
Chaturvedi, SudhirKumar	Lieske, DavidJ.	Tang, Mengling
Chen, Chao	Liu, Cong	Teodoro, Ana
Chen, Shaohua	Liu, Guorui	Thejll, PeterA.
Chen, Yaning	Liu, Ruhai	Tiwari, ArjunPrasad
Coccia, Mario	Liu, Wen-Cheng	vandoninck, Jasper
Coman, Sonia	Lynch, ChristopherJ.	vanFraneker, Jan
Cooke, RichardA.	Magazzino, Cosimo	Verichev, Konstantin
Elsaid, Khaled	Mak, HugoWaiLeung	Vivoni, EnriqueR.
Faiz, MuhammadAbrar	Marcano-Vega, Humfredo	Vrinceanu, NicoletaOlimpia
Fang, Cheng	Michalet, Richard	Wang, Jinfeng
Fernandez, Pilar	Mohamad, Diana	Wang, Shaoli
Ganatsas, Petros	Molot, LewisA.	Wang, Zhifang
Gao, Rui	Murty, P.L.N.	Wanner, Alice
Generowicz, Agnieszka	Naz, BibiS.	Welker, Martin
Goel, Gaurav	Nedjai, Rachid	Yamano, Hiroya
Gomes, Eduardo	Olie, Kees	Zamorska, Magdalena
Gong, Guangcai	Omrany, Hossein	Zhang, Han
Gophen, Moshe	Peng, Yutao	Zhang, Rong
Guo, Bo	Potter, PhillipM.	Zhang, Wanchang
He, Baojie	Povilaitis, Arvydas	Zhang, Xiu-Jun
Hernández-Chover, Vicent	Hu, Zhengyi	Zhang, Xun



Enjoy *AEER* by:

1. [Submitting a manuscript](#)
2. [Joining in volunteer reviewer bank](#)
3. [Joining Editorial Board](#)
4. [Guest editing a special issue](#)

For more details, please visit:

<http://www.lidsen.com/journals/aeer>